

17.5 GHz — 31.5 GHz Low Noise Amplifier

ADH519S

1.0 SCOPE

This specification documents the detail requirements for an internally defined equivalent flow per MIL-PRF-38535 Level V except as modified herein.

The manufacturing flow described in the ADI RF & MICROWAVE STANDARD SPACE LEVEL PRODUCTS PROGRAM is to be considered a part of this specification.

This data specifically details the space grade version of this product. A more detailed operational description and a complete data sheet for commercial product grades can be found at http://www.analog.com/HMC519LC4

2.0 Part Number: The complete part number(s) of this specification follows:

Specific Part Number Description

ADH519R701LSH6 GaAs pHEMT Low Noise Amplifier, 17.5 GHz – 31.5 GHz

3.0 Case Outline

The case outline is as follows:

Outline Letter	<u>Descriptive Designator</u>	<u>Ierminals</u>	<u>Lead Finish</u>	Package style
Χ	EH-16-2	16 Lead	Gold	Ceramic Hermetic SMT (LSH6)

FUNCTIONAL BLOCK DIAGRAM

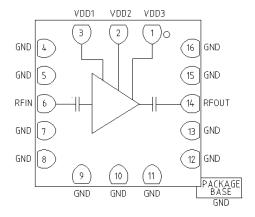


Figure 1 – Functional Block Diagram

Pin Number	Terminal Symbol	Pin Type	Pin Description
1	V_{DD3}	Power	Supply Voltage
2	V_{DD2}	Power	Supply Voltage
3	V_{DD1}	Power	Supply Voltage
4	GND	Power	Ground
5	GND	Power	Ground
6	RF IN	RF I/O	RF IN <u>2</u> /
7	GND	Power	Ground
8	GND	Power	Ground
9	GND	Power	Ground
10	GND	Power	Ground
11	GND	Power	Ground
12	GND	Power	Ground
13	GND	Power	Ground
14	RF OUT	RF I/O	RF OUT <u>2</u> /
15	GND	Power	Ground
16	GND	Power	Ground
Package Bottom	GND	Power	Ground
Package Lid	GND	Power	Package lid is connected to RF/DC ground

Figure 2 – Terminal Connections

 $[\]underline{1}$ / The package bottom has an exposed metal pad that must connect the printed circuit board (PCB) RF/DC ground. $\underline{2}$ / This pin is DC blocked and internally matched to 50 ohms.

4.0 Specifications

4.1. Absolute Maximum Ratings 1/

Drain Bias Voltage (V _{DD1} , V _{DD2} , V _{DD3})	+3.5 Vdc
RF Input Power (RFIN) ($V_{DD1} = V_{DD2} = V_{DD3} = +3.0 \text{ Vdc}$) $\underline{2}$ /	+20 dBm
Channel Temperature	175°C
Continuous P _{diss} (T=85°C)	1.71 W
(derate 19 mW/°C above 85 °C)	
Thermal Resistance (Channel to package bottom) θ_{JC}	52.63 °C/W
Storage temperature	-65°C to 150°C
ESD Sensitivity (HBM)	Class 1A

4.2. Recommended Operating Conditions

Positive Supply voltage (V _{DD})	+2.5 V to +3.5 V
Ambient Operating Temperature Range (T _A)	-40°C to +85°C

4.3. Nominal Operating Performance Characteristics 3/

Saturated Output Power (Psat) (17.5-28.5 GHz)	10.5 dBm
Saturated Output Power (Psat) (28.5-31.5 GHz)	14 dBm
Input Return Loss (S ₁₁) (17.5-28.5 GHz)	3.2 dB
Input Return Loss (S ₁₁) (28.5-31.5 GHz)	4 dB
Output Return Loss (S ₂₂) (17.5-28.5 GHz)	3.5 dB
Output Return Loss (S ₂₂) (28.5-31.5 GHz)	9 dB
Reverse Isolation (S ₁₂) (17.5-28.5 GHz)	27 dB
Reverse Isolation (S ₁₂) (28.5-31.5 GHz)	31 dB
Dynamic I _{DD} at Psat	95 mA

4.4. Radiation Features

Maximum Total Dose Available (dose rate = 50 - 300 rads (Si)/s).... 100K rads (Si)

^{1/} Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions outside of those indicated in the operation sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

^{2/} Frequency = 17.5 GHz - 31.5 GHz $\frac{1}{3}$ / All typical specifications are at T_A = 25°C, V_{DD1} = V_{DD2}, = V_{DD3} = 3V, unless otherwise noted.

TABLE I – ELECTRICAL PERFORMANCE CHARACTERISTICS

Parameter	C	Conditions <u>1</u> / Unless otherwise specified		Group A	Limits		
See notes at end of table	Symbol			Subgroups	Min	Max	Units
RF CHARACTERISTICS			cernea				
Gain	S21	17.5 GHz		4	11.8		dB
				5,6	10.5		
			M,D,P,L,R	4	11.8		
		28.5 GHz		4	11		
				5,6	10		
			M,D,P,L,R	4	11		
		31.5 GHz		4	10.5		
				5,6	9.5		
			M,D,P,L,R	4	10.5		
Gain Variation Over Temp <u>2</u> / <u>3</u> /		17.5 GHz		4,5,6		0.026	dB/°C
	S21 / °C	28.5 GHz		4,5,6		0.026	
		31.5 GHz		4,5,6		0.026	
Noise Figure	NF	17.5 GHz		4		4	dB
				5,6		4.5	
			M,D,P,L,R	4		4	
		28.5 GHz		4		4	
				5,6		4.5	
			M,D,P,L,R	4		4	
		31.5 GHz		4		4.5	
				5,6		5	
			M,D,P,L,R	4		4.5	
Output Power for 1dB	OP1dB	17.5 GHz		4	7.2		dBm
Compression <u>2</u> / <u>3</u> / <u>5</u> /				5	6.5		
				6	8.5		
		28.5 GHz		4	7.2		
				5	6.5		
				6	8.5		
		31.5 GHz		4	8.5		
				5	8		
				6	9.5		
Output Third Order Intercept	OIP3	17.5 GHz		4	17.2		dBm
<u>2</u> / <u>3</u> / <u>6</u> /				5	16		
				6	19		
		28.5 GHz		4	17.2		
				5	16		
				6	19		
		31.5 GHz		4	19.2		
				5	17.5		
				6	20.5		
BIAS AND SUPPLY CURRENT							
Supply Current <u>4</u> /	I_{DD}		_	1,2,3		95	mA
			M,D,P,L,R	1		95	mA

TABLE I NOTES:

- $1/T_A$ nom = 25°C, T_A max = 85°C, and T_A min = -40°C unless otherwise noted, $V_{DD1} = V_{DD2}$, = $V_{DD3} = +3V_{DD3}$
- 2/ Parameter is part of device initial characterization which is only repeated after design and process changes or with subsequent wafer lots.
- 3/ Parameter is not tested post irradiation
- 4/ Supply current measured with no signal at RF IN.
- 5/ Input power sweep -5 dBm to 10 dBm
- $\underline{6}/f_1$ power = f_2 power = -5 dBm, Fixed Delta F = 1 MHz

TABLE IIA - ELECTRICAL TEST REQUIREMENTS:

Test Requirements	Subgroups (in accordance with MIL-PRF-38535, Table III)
Interim Electrical Parameters	1,4
Final Electrical Parameters	1, 4 <u>1</u> / <u>2</u> /
Group A Test Requirements	1, 2, 3, 4, 5, 6
Group C end-point electrical parameters	1, 4 <u>2</u> /
Group D end-point electrical parameters	1,4
Group E end-point electrical parameters	1,4 <u>3</u> /

Table IIA Notes:

TABLE IIB - BURN-IN / LIFE TEST DELTA LIMITS 1/2/3/

Parameter	Symbol	Delta	Units
Gain 18 GHz	S21	±1.0	dB
Gain 28 GHz	S21	±1.5	dB
Gain 31 GHz	S21	±1.5	dB
Supply Current	I _{DD}	±10	%

Table IIB Notes:

^{1/} PDA applies to Table I subgroup 1 and Table IIB delta parameters.

^{2/} See Table IIB for delta parameters
3/ Parameters noted in Table I are not tested post irradiation.

 ^{1/ 240} hour burn in and 1000 hour life test (group C) end point electrical parameters.
 2/ Deltas are performed at room temperature T_A = +25°C only.
 3/ Deltas apply with V_{DD1} = V_{DD2} = V_{DD3} = 3.0V unless otherwise noted

5.0 Burn-In Life Test, and Radiation

5.1. Burn-In Test Circuit, Life Test Circuit

- 5.1.1.The test conditions and circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 test condition D of MIL –STD-883.
- 5.1.2.HTRB is not applicable for this drawing.

5.2. Radiation Exposure Circuit

- 5.2.1. The radiation exposure circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing and acquiring activity upon request. Total dose irradiation testing shall be performed in accordance with MIL-STD-883 method 1019, condition A.
- 5.2.2.ADH519S have been characterized through all levels M, D, P, L, R of irradiation. However, ADH519S is only tested at the "R" level. Pre and Post irradiation values are identical unless otherwise specified in Table IA.

6.0 MIL-PRF-38535 QMLV Exceptions

The manufacturing flow described in the RF & MICROWAVE STANDARD SPACE LEVEL PRODUCTS PROGRAM is to be considered a part of this specification. The brochure describes standard QMLV exceptions for Aerospace products run at the ADI Chelmsford, MA facility.

6.1. Wafer Fabrication

Foundry information is available on request.

6.2. Group D

Group D-5 Salt Atmosphere testing is not being performed.

7.0 Application Circuit

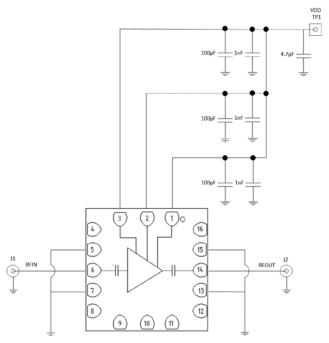


Figure 3 – Application Circuit

8.0 Package Outline Dimensions

The LSH6 package and outline dimensions can be found at http://www.analog.com or upon request.

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
ADH519R701LSH6	-40°C to +85°C	16 Lead Ceramic Leadless SMT	LSH6 (EH-16-2)

Revision History					
Rev	Description of Change	Date			
А	Initial Release	2/14/2020			

